

Notice of References Cited	Application/Control No. 10/554,059		Applicant(s)/Patent Under Reexamination OTOMO ET AL.	
	Examiner ROBERT S. WALTERS JR		Art Unit 1792	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,315,998 A	02-1982	Neckers et al.	525/359.3
*	B	US-6,211,112 B1	04-2001	Ishibashi, Yoshiaki	502/159
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2001-277200	10-2001	Japan	Ishino et al.	B82B 3/00
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lee et al. "Single-Bond Formation and Characterization with a Scanning Tunneling Microscope" Science 286, 1719 (1999).
	V	Costela et al. "N-acetyl-4-nitro-1-naphthylamine as Sensitizer of N,N-dimethylaniline for Photoinitiated Radical Polymerization" Polymer Vol. 41, Issue 22, Oct. 2000.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.